

Supplementary Material

An Expandable Yield Prediction Framework Using Explainable Artificial Intelligence for Semiconductor Manufacturing

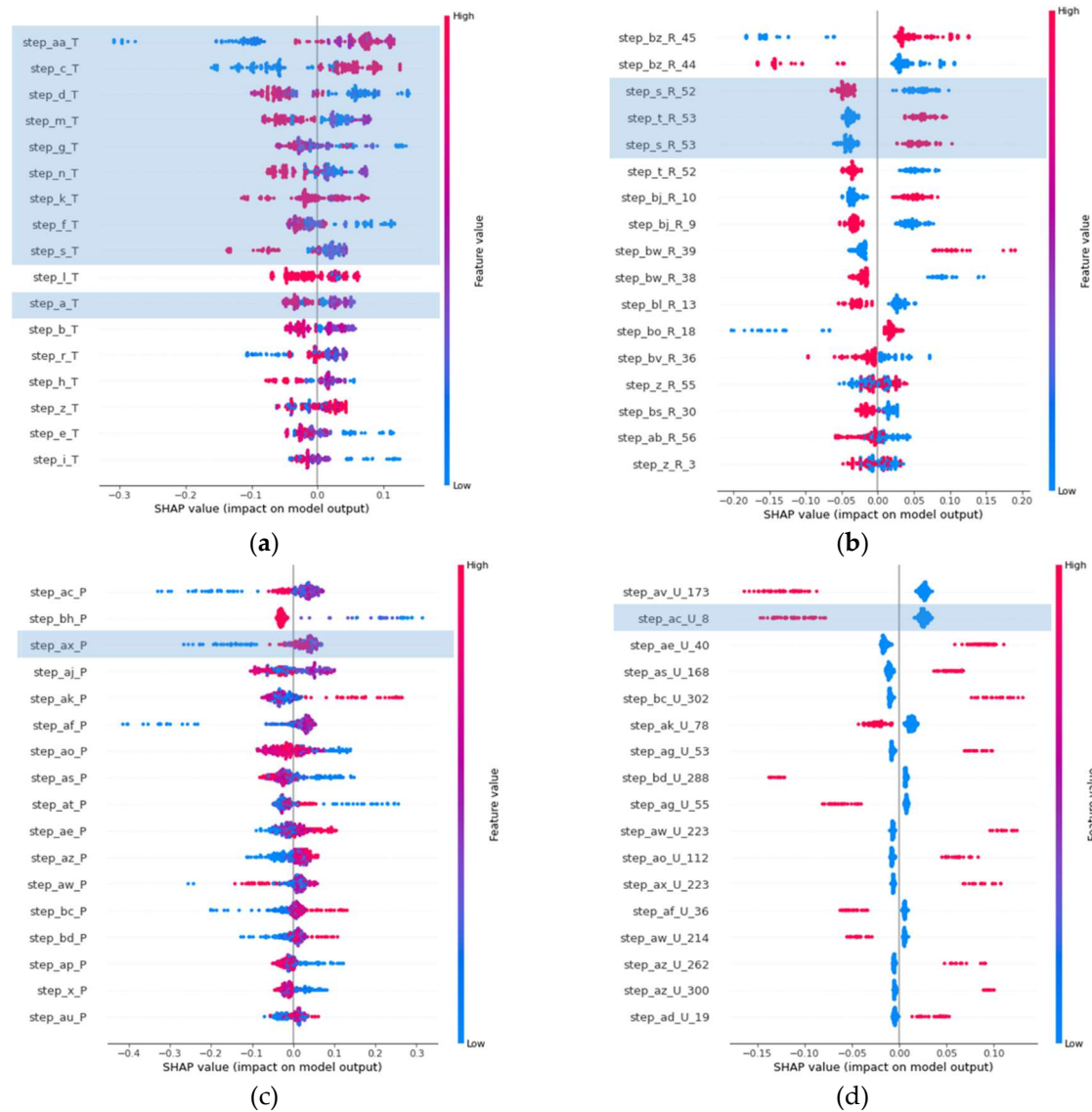


Figure S1. SHAP value plots for the top parameters of individual models based on (a) the dataset of time spans, (b) the dataset of operation programs, (c) the dataset of sensor parameters, and (d) the dataset of instrument units. The marked parameters overlap with those of the model based on the combined datasets.